N- and P-Channel 20-V (D-S) MOSFET

CHARACTERISTICS

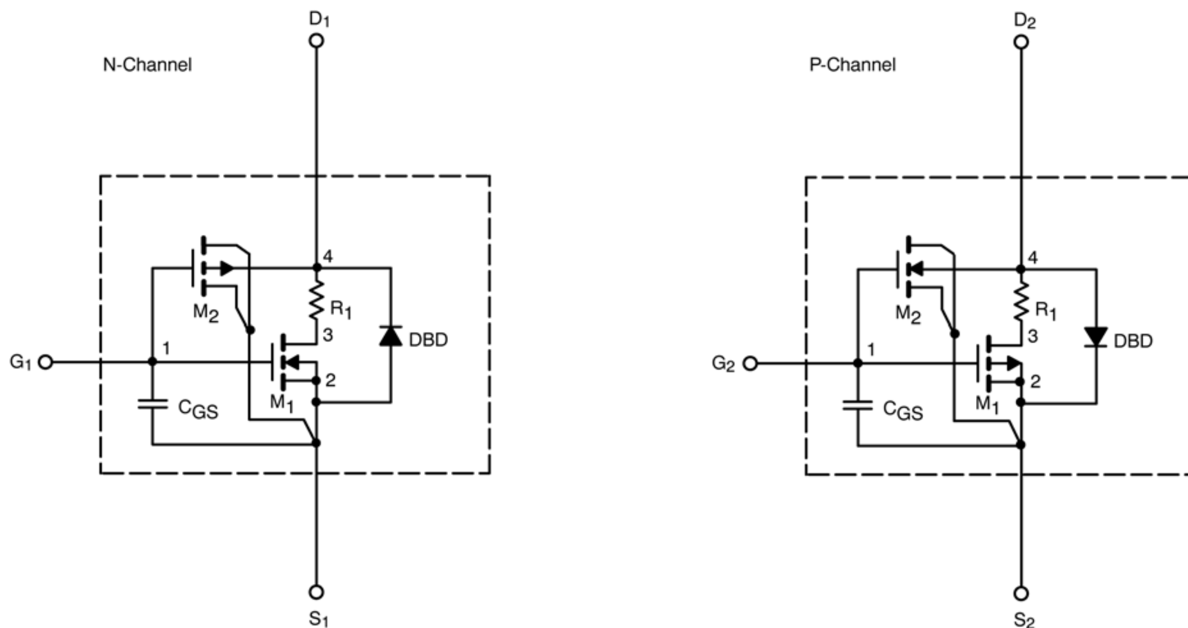
- N- and P-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the −55 to 125°C Temperature Range
- Model the Gate Charge, Transient, and Diode Reverse Recovery Characteristics

DESCRIPTION

The attached spice model describes the typical electrical characteristics of the n- and p-channel vertical DMOS. The subcircuit model is extracted and optimized over the −55 to 125°C temperature ranges under the pulsed 0-V to 10-V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched C_{gd} model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

SUBCIRCUIT MODEL SCHEMATIC



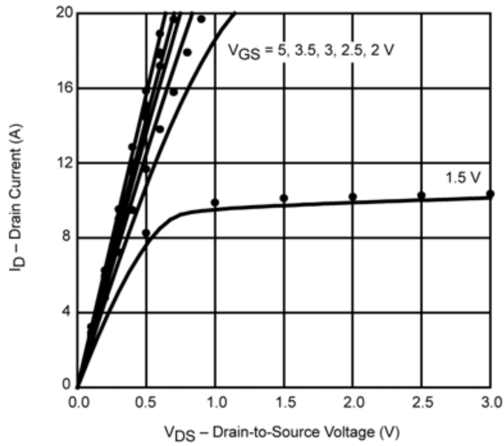
This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designers should refer to the appropriate data sheet of the same number for guaranteed specification limits.

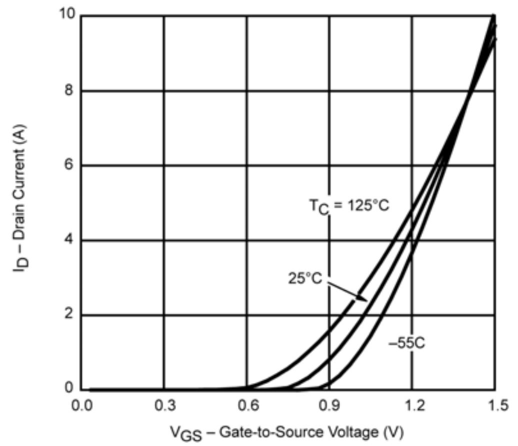
SPECIFICATIONS (T_J = 25°C UNLESS OTHERWISE NOTED)						
Parameter	**Symbol**	**Test Condition**		**Simulated Data**	**Measured Data**	**Unit**
Static						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, I_D = 250 µA	N-Ch	0.50		
		$V_{DS} = V_{GS}$, I_D = –250 µA	P-Ch	0.80		
On-State Drain Current[a]	$I_{D(on)}$	V_{DS} < 5 V, V_{GS} = 4.5 V	N-Ch	117		A
		V_{DS} < –5 V, V_{GS} = –4.5 V	P-Ch	60		
Drain-Source On-State Resistance[a]	$r_{DS(on)}$	V_{GS} = 4.5 V, I_D = 4.4 A	N-Ch	0.032	0.032	Ω
		V_{GS} = –4.5 V, I_D = –3.3 A	P-Ch	0.063	0.060	
		V_{GS} = 2.5 V, I_D = 4.1 A	N-Ch	0.038	0.037	
		V_{GS} = –2.5 V, I_D = –2.8 A	P-Ch	0.082	0.083	
		V_{GS} = 1.8 V, I_D = 1.8 A	N-Ch	0.046	0.046	
		V_{GS} = –1.8 V, I_D = –0.76 A	P-Ch	0.107	0.108	
Forward Transconductance[a]	g_{fs}	V_{DS} = 10 V, I_D = 4.4 A	N-Ch	23	22	S
		V_{DS} = –10 V, I_D = –3.3 A	P-Ch	11	9	
Diode Forward Voltage[a]	V_{SD}	I_S = 1.2 A	N-Ch	0.72	0.80	V
		I_S = –1A	P-Ch	0.78	- 080	
Dynamic[b]						
Input Capacitance	C_{iss}	N-Channel V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz P-Channel V_{DS} = –10 V, V_{GS} = 0 V, f = 1 MHz	N-Ch	605	520	pF
			P-Ch	589	455	
Output Capacitance	C_{oss}		N-Ch	96	100	
			P-Ch	103	105	
Reverse Transfer Capacitance	C_{rss}		N-Ch	62	60	
			P-Ch	57	65	
Total Gate Charge	Q_g	V_{DS} = 10 V, V_{GS} = 8 V, I_D = 4.4 A	N-Ch	8.1	10.5	nC
		V_{DS} = – 10 V, V_{GS} = –8 V, I_D = –4.6 A	P-Ch	8.4	9.1	
		N-Channel V_{DS} = 10 V, V_{GS} = 4.5 V, I_D = 4.4 A P-Channel V_{DS} = –10 V, V_{GS} = –4.5 V, I_D = –1.8 A	N-Ch	5	6	
			P-Ch	5	5.5	
Gate-Source Charge	Q_{gs}		N-Ch	0.91	0.91	
			P-Ch	0.75	0.75	
Gate-Source Charge	Q_{gs}		N-Ch	0.70	0.70	
			P-Ch	1.5	1.5	

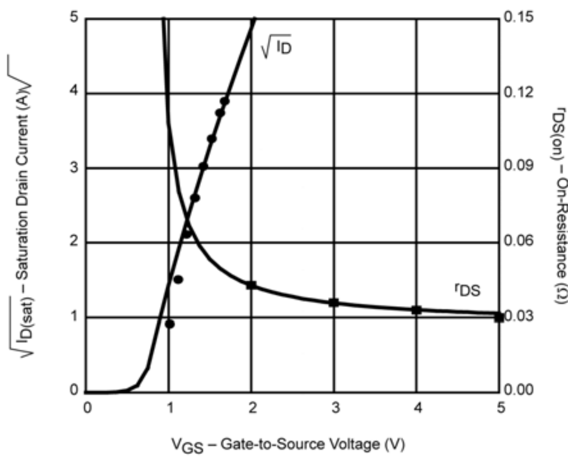
Notes
a. Pulse test; pulse width ≤ 300 µs, duty cycle ≤ 2%.
b. Guaranteed by design, not subject to production testing.

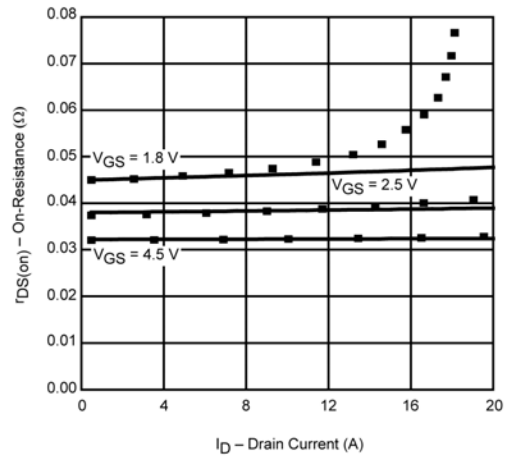
COMPARISON OF MODEL WITH MEASURED DATA (T_J=25°C UNLESS OTHERWISE NOTED)

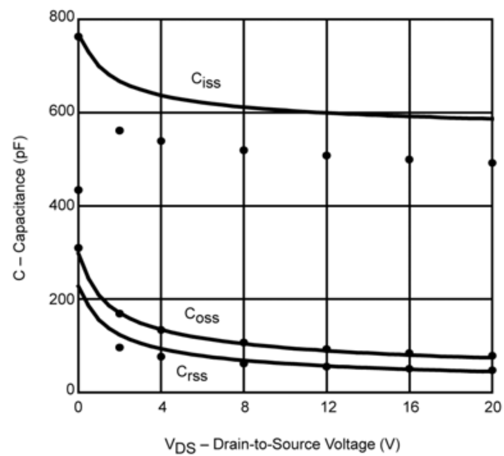
N-Channel MOSFET

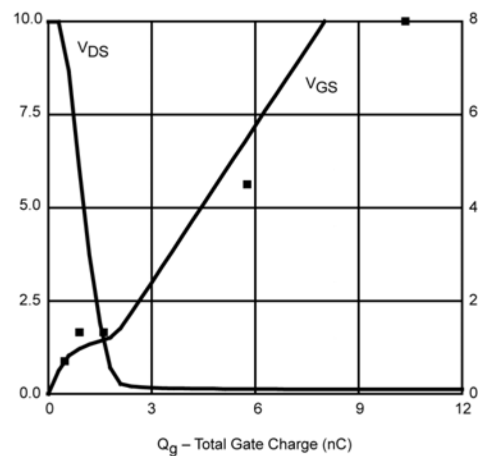






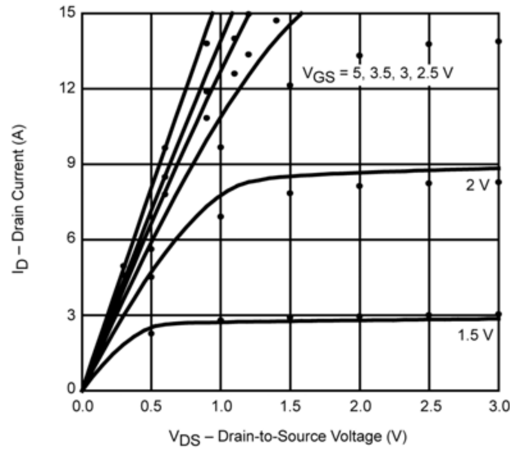


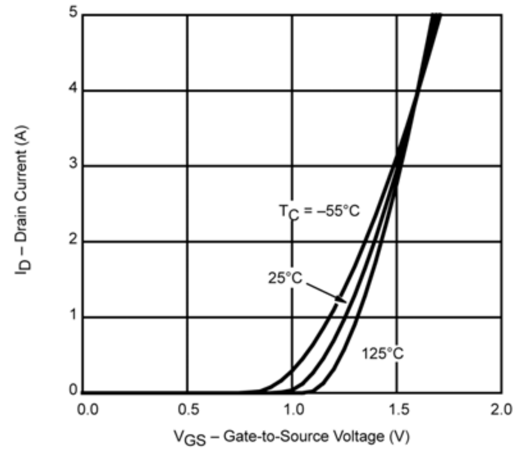


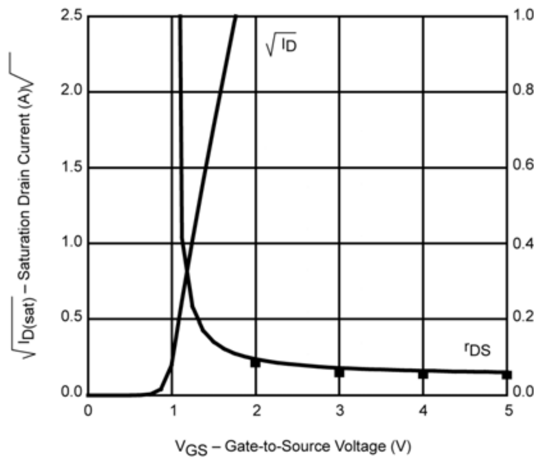


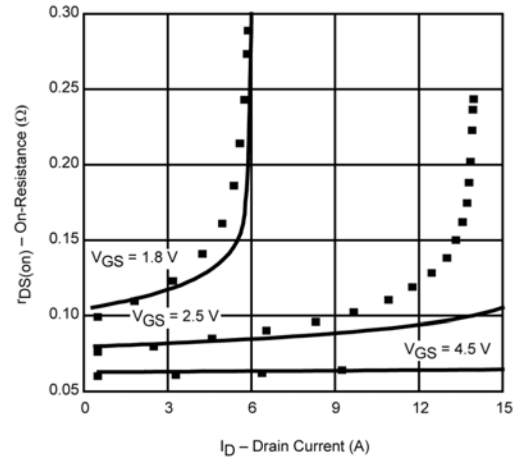
Note: Dots and squares represent measured data.

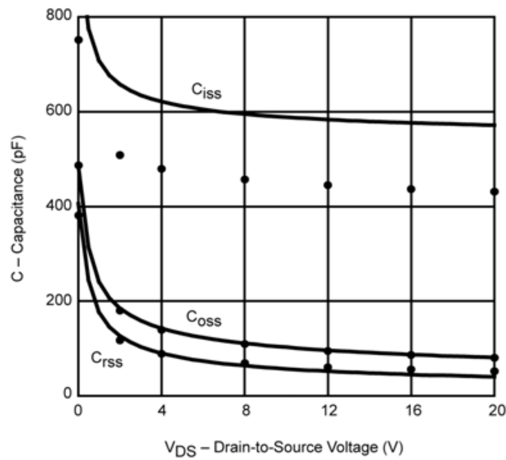
P-Channel MOSFET

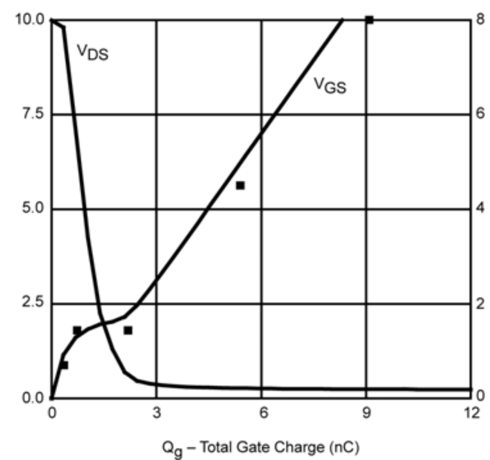












Note: Dots and squares represent measured data.